Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,476	MATHIS ET AL.
Examiner	Art Unit
Mark W. Bockelman	3766

				
SEARCHED				
Class	Subclass	Date	Examiner	
607	9,15,	1-7-67	m.B	
· · · · · · · · · · · · · · · · · · ·				
		•		
_		,	•	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		<u>. </u>		

SEARCH (INCLUDING SEAF		')
	DATE	EXMR
<u> </u>		
•		
•		